



Welcome to [E-XFL.COM](https://www.e-xfl.com)

### Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

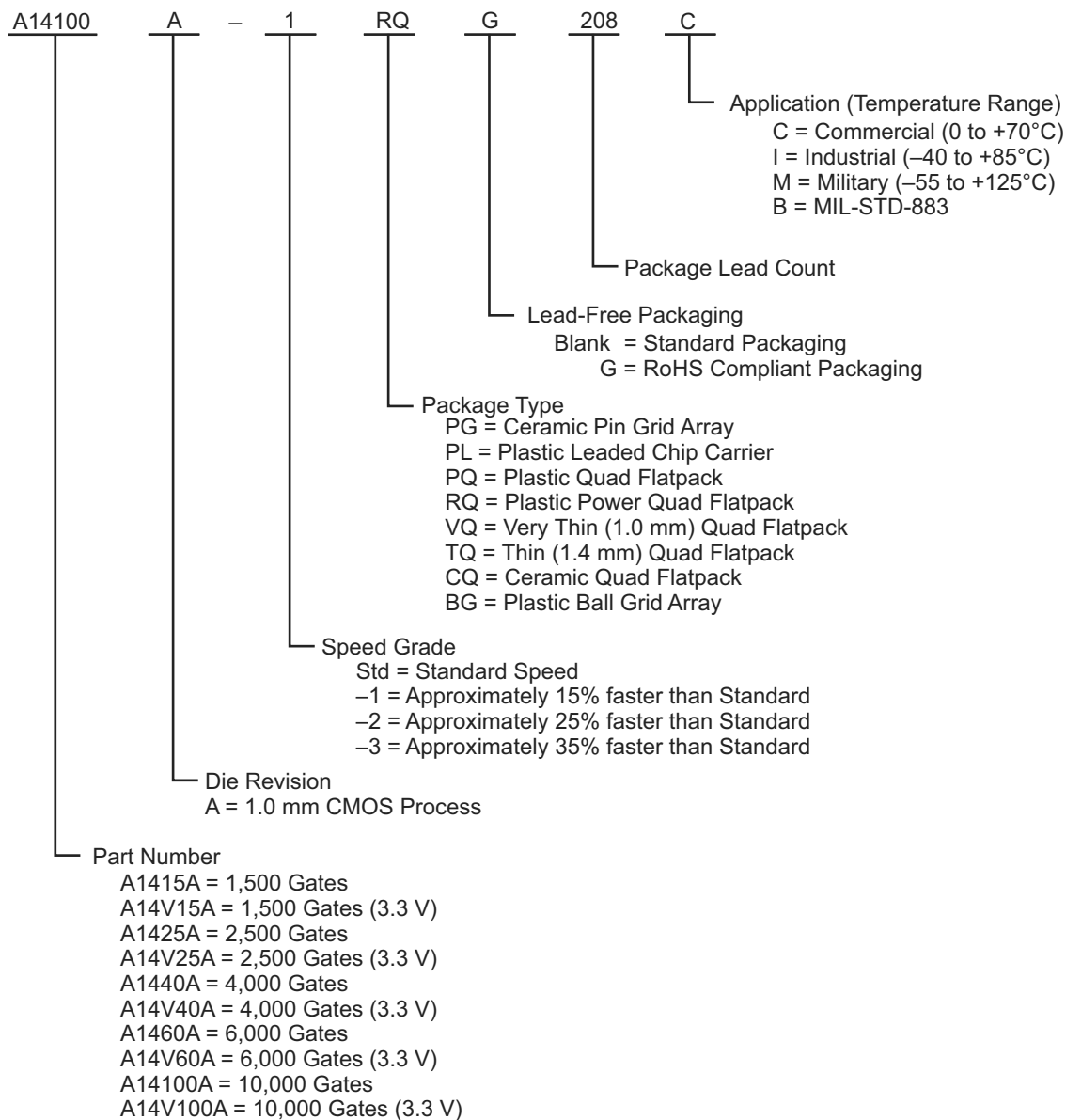
### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	848
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	167
Number of Gates	6000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microsemi/a1460a-1pq208c">https://www.e-xfl.com/product-detail/microsemi/a1460a-1pq208c</a>

## Ordering Information



### Notes:

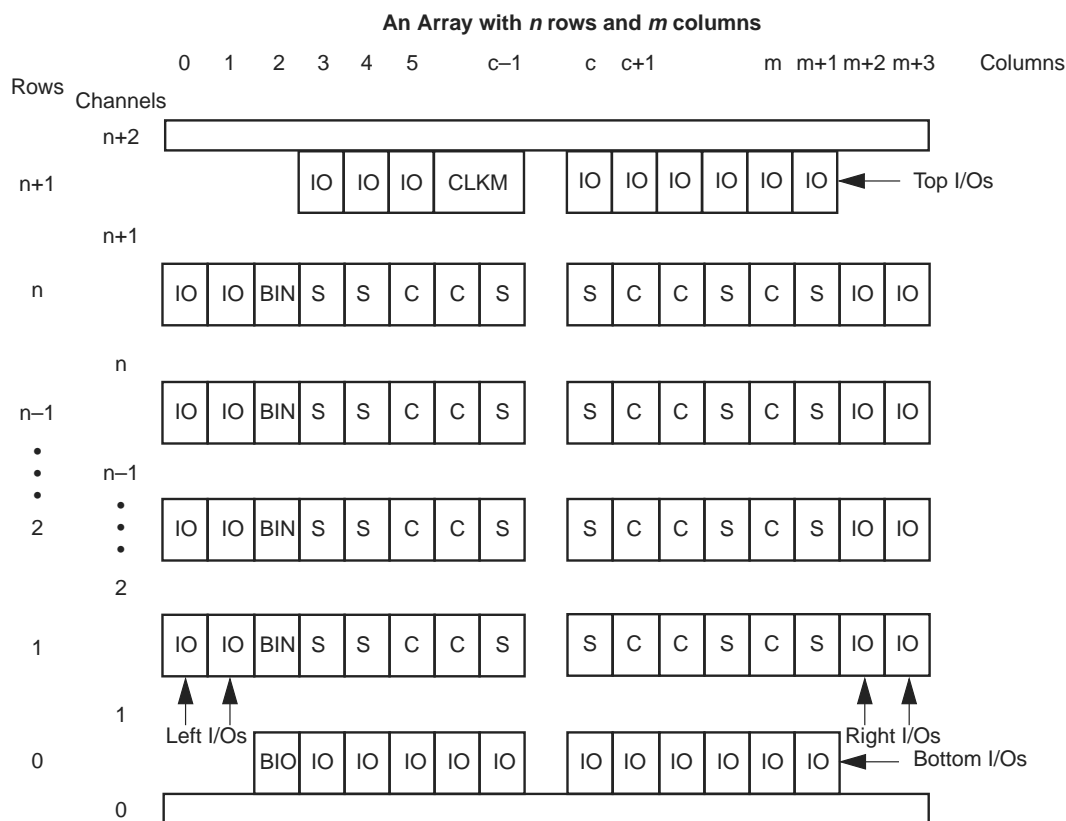
- The –2 and –3 speed grades have been discontinued.
- The Ceramic Pin Grid Array packages PG100, PG133, and PG175 have been discontinued in all device densities, speed grades, and temperature grades.
- The Plastic Ball Grid Array package BG225 has been discontinued in all device densities (specifically for A1460A), all speed grades, and all temperature grades.
- Military Grade devices are no longer available for the A1440A device.
- For more information about discontinued devices, refer to the Product Discontinuation Notices (PDNs) listed below, available on the Microsemi SoC Products Group website:
  - PDN March 2001
  - PDN 0104
  - PDN 0203
  - PDN 0604
  - PDN 1004

## 2 – Detailed Specifications

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

### Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.



**Figure 2-1 • Generalized Floor Plan of ACT 3 Device**

## Package Thermal Characteristics

The device junction to case thermal characteristic is  $\theta_{jc}$ , and the junction to ambient air characteristic is  $\theta_{ja}$ . The thermal characteristics for  $\theta_{ja}$  are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a CPGA 175-pin package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. (°C)} - \text{Max. ambient temp. (°C)}}{\theta_{ja} \text{ °C/W}} = \frac{150^{\circ}\text{C} - 70^{\circ}\text{C}}{25^{\circ}\text{C/W}} = 3.2 \text{ W}$$

EQ 2

**Table 2-8 • Package Thermal Characteristics**

Package Type*	Pin Count	$\theta_{jc}$	$\theta_{ja}$ Still Air	$\theta_{ja}$ 300 ft./min.	Units
Ceramic Pin Grid Array	100	20	35	17	°C/W
	133	20	30	15	°C/W
	175	20	25	14	°C/W
	207	20	22	13	°C/W
	257	20	15	8	°C/W
Ceramic Quad Flatpack	132	13	55	30	°C/W
	196	13	36	24	°C/W
	256	13	30	18	°C/W
Plastic Quad Flatpack	100	13	51	40	°C/W
	160	10	33	26	°C/W
	208	10	33	26	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	11	32	25	°C/W
Power Quad Flatpack	208	0.4	17	13	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Plastic Ball Grid Array	225	10	25	19	°C/W
	313	10	23	17	°C/W

Note: Maximum power dissipation in still air:

PQ160 = 2.4 W

PQ208 = 2.4 W

PQ100 = 1.6 W

VQ100 = 1.9 W

TQ176 = 2.5 W

PL84 = 2.2 W

RQ208 = 4.7 W

BG225 = 3.2 W

BG313 = 3.5 W

Equivalent capacitance is calculated by measuring ICC active at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency independent so that the results may be used over a wide range of operating conditions. Equivalent capacitance values are shown in Figure 2-10.

**Table 2-10 • CEQ Values for Microsemi FPGAs**

Item	CEQ Value
Modules (C <sub>EQM</sub> )	6.7
Input Buffers (C <sub>EQI</sub> )	7.2
Output Buffers (C <sub>EQO</sub> )	10.4
Routed Array Clock Buffer Loads (C <sub>EQCR</sub> )	1.6
Dedicated Clock Buffer Loads (C <sub>EQCD</sub> )	0.7
I/O Clock Buffer Loads (C <sub>EQCI</sub> )	0.9

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. EQ 5 shows a piece-wise linear summation over all components.

$$\begin{aligned}
 \text{Power} = & VCC^2 * [(m * C_{EQM} * f_m)_{\text{modules}} + (n * C_{EQI} * f_n)_{\text{inputs}} \\
 & + (p * (C_{EQO} + C_L) * f_p)_{\text{outputs}} \\
 & + 0.5 * (q_1 * C_{EQCR} * f_{q1})_{\text{routed\_Clk1}} + (r_1 * f_{q1})_{\text{routed\_Clk1}} \\
 & + 0.5 * (q_2 * C_{EQCR} * f_{q2})_{\text{routed\_Clk2}} \\
 & + (r_2 * f_{q2})_{\text{routed\_Clk2}} + 0.5 * (s_1 * C_{EQCD} * f_{s1})_{\text{dedicated\_Clk}} \\
 & + (s_2 * C_{EQCI} * f_{s2})_{\text{IO\_Clk}}]
 \end{aligned}$$

EQ 5

Where:

m = Number of logic modules switching at f<sub>m</sub>

n = Number of input buffers switching at f<sub>n</sub>

p = Number of output buffers switching at f<sub>p</sub>

q<sub>1</sub> = Number of clock loads on the first routed array clock

q<sub>2</sub> = Number of clock loads on the second routed array clock

r<sub>1</sub> = Fixed capacitance due to first routed array clock

r<sub>2</sub> = Fixed capacitance due to second routed array clock

s<sub>1</sub> = Fixed number of clock loads on the dedicated array clock

s<sub>2</sub> = Fixed number of clock loads on the dedicated I/O clock

C<sub>EQM</sub> = Equivalent capacitance of logic modules in pF

C<sub>EQI</sub> = Equivalent capacitance of input buffers in pF

C<sub>EQO</sub> = Equivalent capacitance of output buffers in pF

C<sub>EQCR</sub> = Equivalent capacitance of routed array clock in pF

C<sub>EQCD</sub> = Equivalent capacitance of dedicated array clock in pF

C<sub>EQCI</sub> = Equivalent capacitance of dedicated I/O clock in pF

C<sub>L</sub> = Output lead capacitance in pF

f<sub>m</sub> = Average logic module switching rate in MHz

f<sub>n</sub> = Average input buffer switching rate in MHz

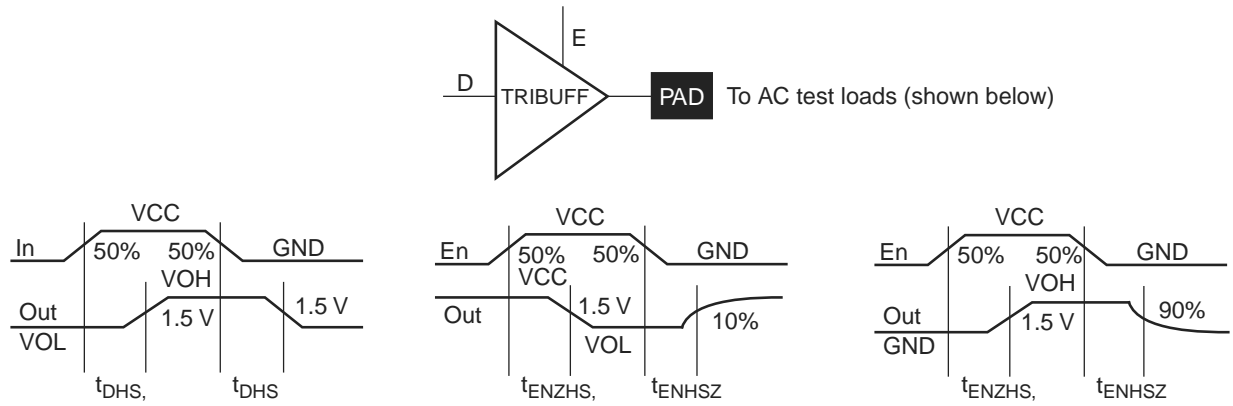
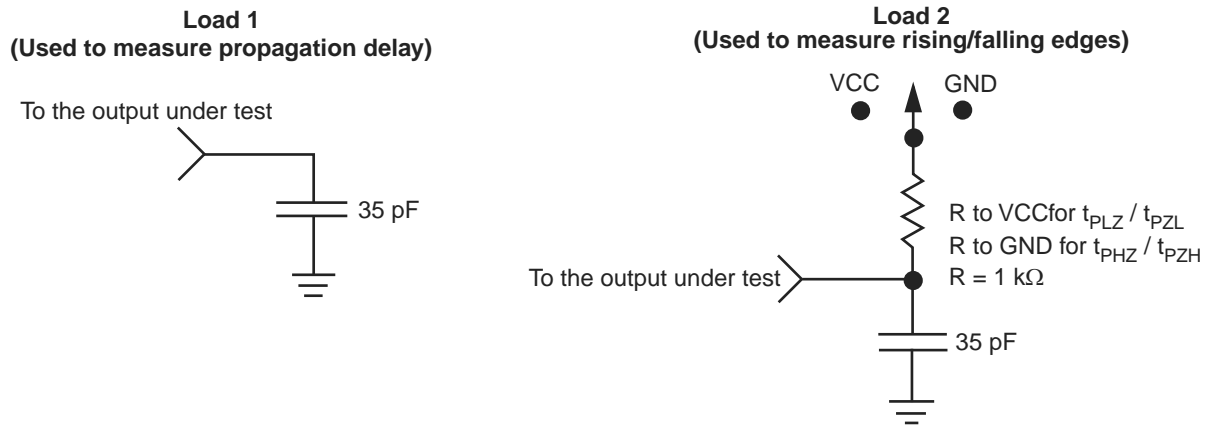
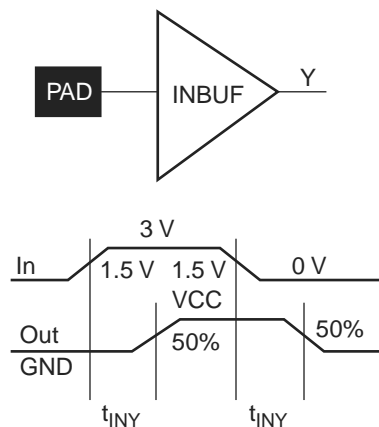
f<sub>p</sub> = Average output buffer switching rate in MHz

f<sub>q1</sub> = Average first routed array clock rate in MHz

f<sub>q2</sub> = Average second routed array clock rate in MHz

f<sub>s1</sub> = Average dedicated array clock rate in MHz

f<sub>s2</sub> = Average dedicated I/O clock rate in MHz


**Figure 2-11 • Output Buffers**

**Figure 2-12 • AC Test Loads**

**Figure 2-13 • Input Buffer Delays**

## A1415A, A14V15A Timing Characteristics

**Table 2-18 • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C<sup>1</sup>**

Logic Module Propagation Delays <sup>2</sup>		–3 Speed <sup>3</sup>		–2 Speed <sup>3</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>PD</sub>	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t <sub>CO</sub>	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t <sub>CLR</sub>	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
<b>Predicted Routing Delays<sup>4</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>Logic Module Sequential Timing</b>												
t <sub>SUD</sub>	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t <sub>HD</sub>	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>SUD</sub>	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t <sub>HD</sub>	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>WASYN</sub>	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t <sub>WCLKA</sub>	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>MAX</sub>	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

**Notes:**

- VCC = 3.0 V for 3.3 V specifications.
- For dual-module macros, use t<sub>PD</sub> + t<sub>RD1</sub> + t<sub>PDn</sub> + t<sub>CO</sub> + t<sub>RD1</sub> + t<sub>PDn</sub> or t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>SUD</sub>, whichever is appropriate.
- The –2 and –3 speed grades have been discontinued. Please refer to the Product Discontinuation Notices (PDNs) listed below:  
PDN March 2001  
PDN 0104  
PDN 0203  
PDN 0604  
PDN 1004
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

## A1425A, A14V25A Timing Characteristics (continued)

**Table 2-25 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Dedicated (hardwired) I/O Clock Network		–3 Speed <sup>1</sup>		–2 Speed <sup>1</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>ILOCKH</sub>	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t <sub>IOPWH</sub>	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>IPOWL</sub>	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>IOSAPW</sub>	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t <sub>ILOCKSW</sub>	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t <sub>IOP</sub>	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>IOMAX</sub>	Maximum Frequency		250		200		150		125		100	MHz
<b>Dedicated (hardwired) Array Clock</b>												
t <sub>HCKH</sub>	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>HCKL</sub>	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t <sub>HPWH</sub>	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t <sub>HPWL</sub>	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t <sub>HCKSW</sub>	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t <sub>HP</sub>	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f <sub>HMAX</sub>	Maximum Frequency		250		200		150		125		100	MHz
<b>Routed Array Clock Networks</b>												
t <sub>RCKH</sub>	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t <sub>RCKL</sub>	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t <sub>RPWH</sub>	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>RPWL</sub>	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t <sub>RCKSW</sub>	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t <sub>RP</sub>	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f <sub>RMAX</sub>	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
<b>Clock-to-Clock Skews</b>												
t <sub>IOHCKSW</sub>	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t <sub>IORCKSW</sub>	I/O Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	
t <sub>HRCKSW</sub>	H-Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

**Notes:**

- The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
- Delays based on 35 pF loading.

## A1440A, A14V40A Timing Characteristics (continued)

**Table 2-27 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

I/O Module Input Propagation Delays		–3 Speed <sup>1</sup>		–2 Speed <sup>1</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INY</sub>	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t <sub>ICKY</sub>	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCKY</sub>	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>ICLRY</sub>	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCLRY</sub>	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
<b>Predicted Input Routing Delays<sup>2</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>I/O Module Sequential Timing (wrt IOCLK pad)</b>												
t <sub>INH</sub>	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input F-F Data Setup	1.8		1.7		2.0		2.3		2.3		ns
t <sub>IDEH</sub>	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>IDESU</sub>	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t <sub>OUTH</sub>	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t <sub>OUTSU</sub>	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t <sub>ODEH</sub>	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f <sub>ODESU</sub>	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

**Notes:**

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

## A1440A, A14V40A Timing Characteristics (continued)

Table 2-28 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C

I/O Module – TTL Output Timing <sup>1</sup>		–3 Speed <sup>2</sup>		–2 Speed <sup>2</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>DHS</sub>	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		8.5		8.5		9.5		11.0		14.3	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing <sup>1</sup>												
t <sub>DHS</sub>	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.1		11.8		14.3	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

**Notes:**

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

## A14100A, A14V100A Timing Characteristics (continued)

**Table 2-35 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

I/O Module Input Propagation Delays		–3 Speed <sup>1</sup>		–2 Speed <sup>1</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INY</sub>	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t <sub>ICKY</sub>	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCKY</sub>	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>ICLRY</sub>	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCLRY</sub>	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
<b>Predicted Input Routing Delays<sup>2</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>I/O Module Sequential Timing (wrt IOCLK pad)</b>												
t <sub>INH</sub>	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input F-F Data Setup	1.2		1.4		1.5		1.8		1.8		ns
t <sub>IDEH</sub>	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>IDESU</sub>	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t <sub>OUTH</sub>	Output F-F Data hold	0.7		0.8		1.0		1.0		1.0		ns
t <sub>OUTSU</sub>	Output F-F Data Setup	0.7		0.8		1.0		1.0		1.0		ns
t <sub>ODEH</sub>	Output Data Enable Hold	0.3		0.4		0.5		0.5		0.5		ns
f <sub>ODESU</sub>	Output Data Enable Setup	1.3		1.5		2.0		2.0		2.0		ns

Notes: \*

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

## Pin Descriptions

### **CLKA**                      **Clock A (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **CLKB**                      **Clock B (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **GND**                      **Ground**

LOW supply voltage.

### **HCLK**                      **Dedicated (Hard-wired) Array Clock (Input)**

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

### **I/O**                      **Input/Output (Input, Output)**

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

### **IOCLK**                      **Dedicated (Hard-wired) I/O Clock (Input)**

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

### **IOPCL**                      **Dedicated (Hard-wired) I/O Preset/Clear (Input)**

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

### **MODE**                      **Mode (Input)**

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

### **NC**                      **No Connection**

This pin is not connected to circuitry within the device.

### **PRA**                      **Probe A (Output)**

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

### **PRB**                      **Probe B (Output)**

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

### **SDI**                      **Serial Data Input (Input)**

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

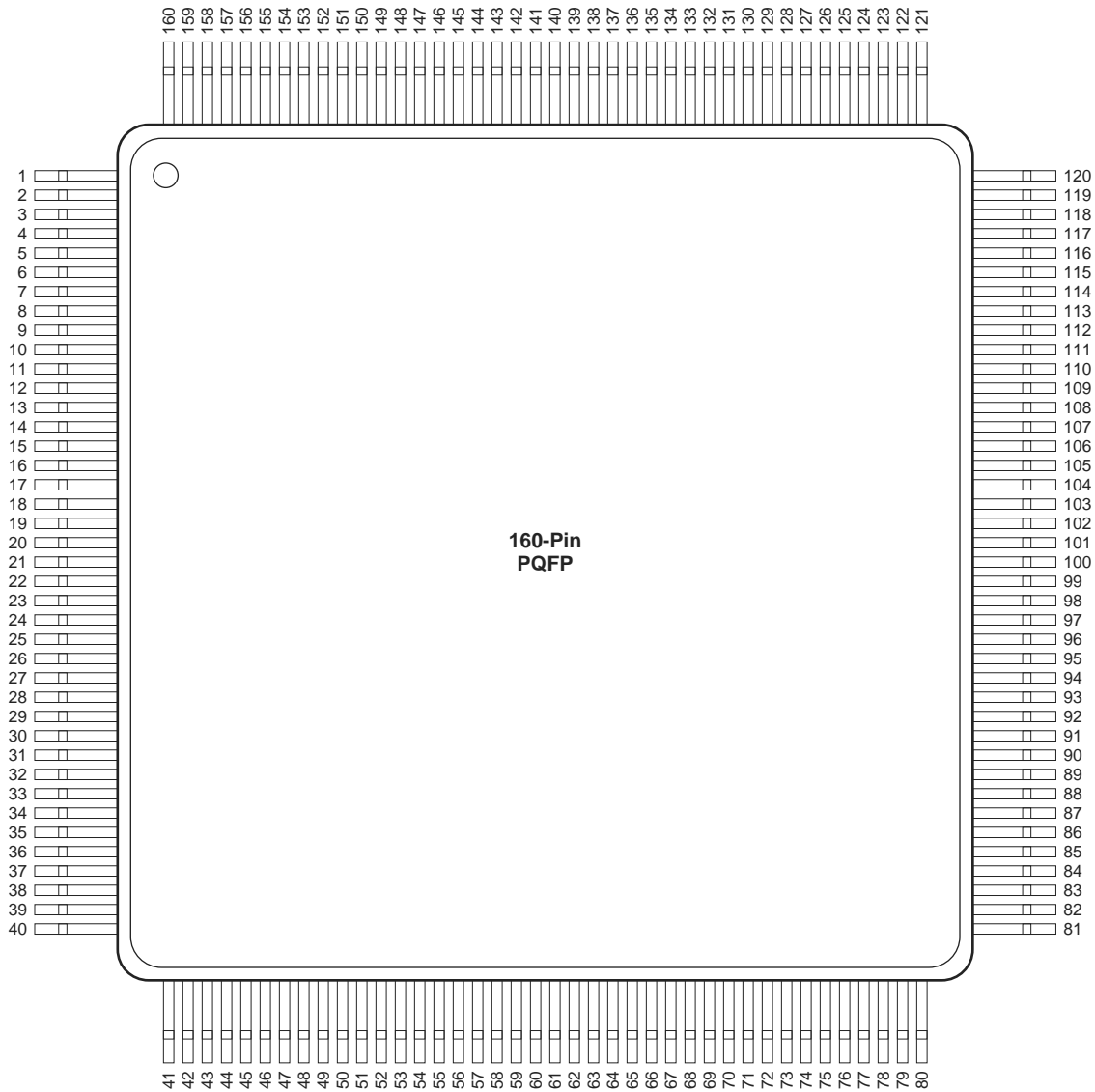


PL84			
Pin Number	A1415, A14V15 Function	A1425, A14V25 Function	A1440, A14V40 Function
1	VCC	VCC	VCC
2	GND	GND	GND
3	VCC	VCC	VCC
4	PRA, I/O	PRA, I/O	PRA, I/O
11	DCLK, I/O	DCLK, I/O	DCLK, I/O
12	SDI, I/O	SDI, I/O	SDI, I/O
16	MODE	MODE	MODE
27	GND	GND	GND
28	VCC	VCC	VCC
40	PRB, I/O	PRB, I/O	PRB, I/O
41	VCC	VCC	VCC
42	GND	GND	GND
43	VCC	VCC	VCC
45	HCLK, I/O	HCLK, I/O	HCLK, I/O
52	SDO	SDO	SDO
53	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
59	VCC	VCC	VCC
60	VCC	VCC	VCC
61	GND	GND	GND
68	VCC	VCC	VCC
69	GND	GND	GND
74	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
83	CLKA, I/O	CLKA, I/O	CLKA, I/O
84	CLKB, I/O	CLKB, I/O	CLKB, I/O

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

## PQ160

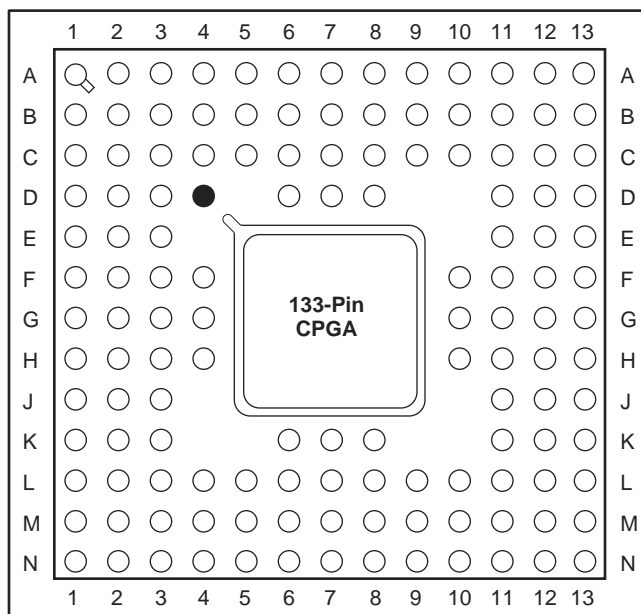


*Note:* This is the top view of the package

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

## PG133

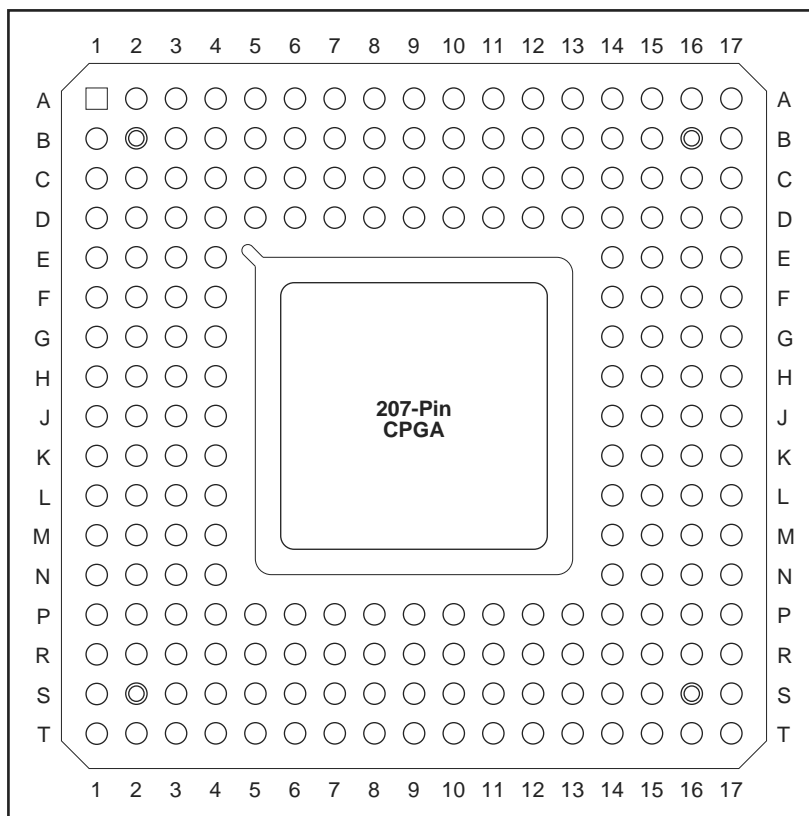


*Note: This is the top view.*

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

## PG207



*Note: This is the top view.*

### Note

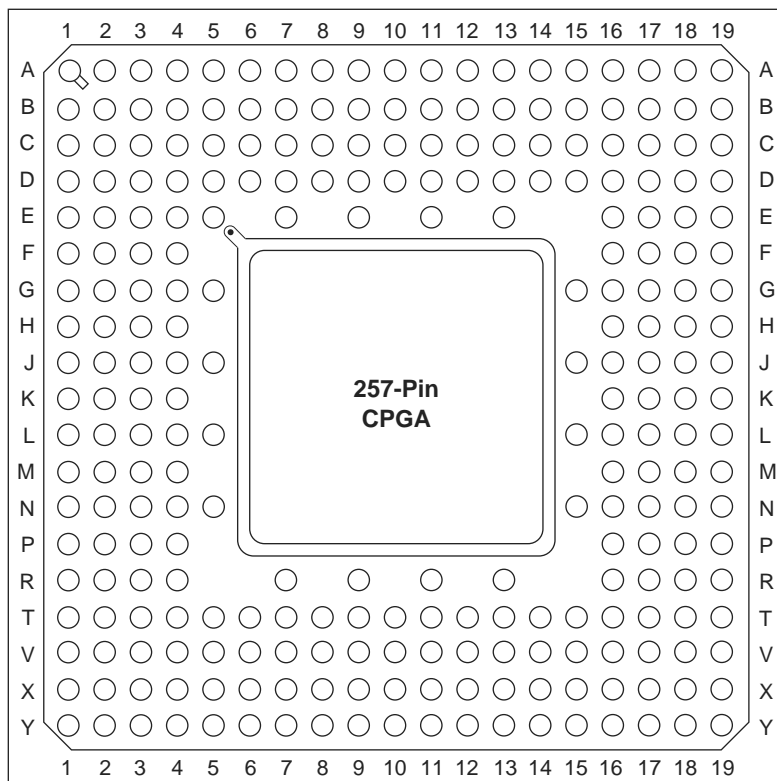
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

**Notes:**

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

## PG257



*Note: This is the top view.*

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

## 4 – Datasheet Information

### List of Changes

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page
Revision 3 (January 2012)	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35820).	2-21
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35820).	3-1
Revision 2 (September 2011)	The ACT 3 datasheet was formatted newly in the style used for current datasheets. The same information is present (other than noted in the list of changes for this revision) but divided into chapters.	N/A
	The datasheet was revised to note in multiple places that speed grades –2 and –3 have been discontinued. The following device/package combinations have been discontinued for all speed grades and temperatures (SAR 33872): A1415 PG100 A1425 PG133 A1440 PG175 A1460 BG225 Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004.	I and others
	The "Features" section was revised to state the clock-to-output time and on-chip performance for –1 speed grade as 9.0 ns and 186 MHz. The "General Description" section was revised in accordance (SAR 33872).	I
	The maximum performance values were updated in Table 1 • ACT 3 Family Product Information, and now reflect worst-case commercial for the –1 speed grade (SAR 33872).	I
	The "Product Plan" table was updated as follows to conform to current offerings (SAR 33872): The A1415A device is offered in PL84, PG100, and VQ100 packages for Military application. The A1440A device is offered in TQ176 and VQ100 packages for Industrial application.	III
	Table 1-1 • Chip-to-Chip Performance (worst-case commercial) was updated to include data for all speed grades instead of only –3 (SAR 33872).	1-2
	Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade) was revised to reflect values for the –1 speed grade (SAR 33872).	1-1
	Figure 2-10 • Timing Model was updated to show data for the –1 speed grade instead of –3 (SAR 33872).	2-16
	Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions was updated to include data for all speed grades instead of only –3 (SAR 33872).	2-20
	Package names used in the "Package Pin Assignments" section and throughout the document were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 27395).	3-1

Revision	Changes	Page
Revision 2 (continued)	In the "Package Pin Assignments" section, notes were added to the pin tables for the following packages, stating that they are discontinued: "BG225" "PG100" "PG133" "PG175"	3-20 3-24 3-26 3-28
Revision 1 (June 2006)	RoHS compliant information was added to the "Ordering Information" section.	II